

A large, light blue decorative graphic consisting of a thick, curved line that forms a partial circle, with a small circle at its top center.

IGBT

TRENCHSTOP™ IGBT3 Chip  
SIGC32T120R3LE

Data Sheet

Industrial Power Control



# SIGC32T120R3LE

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## Table of Contents

Features and Applications.....	3
Mechanical Parameters.....	3
Maximum Ratings.....	4
Static and Electrical Characteristics .....	4
Further Electrical Characteristics .....	5
Chip Drawing.....	6
Revision History .....	7
Relevant Application Notes .....	7
Legal Disclaimer .....	8

## TRENCHSTOP™ IGBT3 Chip

### Features:

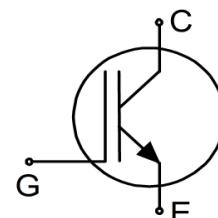
- 1200V trench & field stop technology
- Low turn-off losses
- Short tail current
- Positive temperature coefficient
- Easy paralleling

### Recommended for:

- Power modules

### Applications:

- Drives



Chip Type	$V_{CE}$	$I_{cn}^1$	Die Size	Package
SIGC32T120R3LE	1200V	25A	6.5mm x 4.87mm	Sawn on foil

### Mechanical Parameters

Die size	6.5 x 4.87		mm <sup>2</sup>
Emitter pad size	See chip drawing		
Gate pad size	1.139 x 1.139		
Area total	31.665		
Thickness	120		µm
Wafer size	200		mm
Maximum possible chips per wafer	864		
Passivation frontside	Photoimide		
Pad metal	3200nm AlSiCu		
Backside metal	Ni Ag – system To achieve a reliable solder connection it is strongly recommended not to consume the Ni layer completely during production process		
Die bond	Electrically conductive epoxy glue and soft solder		
Wire bond	Al, ≤500µm		
Reject ink dot size	Ø 0.65mm; max. 1.2mm		
Storage environment	for original and sealed MBB bags	Ambient atmosphere air, temperature 17°C – 25°C, <6 months	
	for open MBB bags	Acc. to IEC62258-3: atmosphere >99% Nitrogen or inert gas, humidity <25%RH, temperature 17°C – 25°C, <6 months	

<sup>1</sup> Nominal collector current at  $T_C=100^\circ\text{C}$  for chip packaged in TO packages, see application example cited on page 5.

## Maximum Ratings

Parameter	Symbol	Value	Unit
Collector-emitter voltage, $T_{vj}=25^{\circ}\text{C}$	$V_{CE}$	1200	V
DC collector current, limited by $T_{vj\text{ max}}^2$	$I_C$	-	A
Pulsed collector current, $t_p$ limited by $T_{vj\text{ max}}^3$	$I_{C,puls}$	75	A
Gate-emitter voltage	$V_{GE}$	$\pm 20$	V
Junction temperature range	$T_{vj}$	-55 ... +175	$^{\circ}\text{C}$
Operating junction temperature	$T_{vj}$	-55 ... +150	$^{\circ}\text{C}$
Short circuit data <sup>3/4</sup> $V_{GE}=15\text{V}$ , $V_{CC}=900\text{V}$ , $T_{vj}=125^{\circ}\text{C}$	$t_{sc}$	10	$\mu\text{s}$
Reverse bias safe operating area <sup>3</sup> (RBSOA)	$I_{C,max}=50\text{A}$ , $V_{CE,max}=1200\text{V}$ , $T_{vj}\leq 125^{\circ}\text{C}$		

## Static Characteristics (tested on wafer), $T_{vj}=25^{\circ}\text{C}$

Parameter	Symbol	Conditions	Value			Unit
			min.	typ.	max.	
Collector-emitter breakdown voltage	$V_{(BR)CES}$	$V_{GE}=0\text{V}$ , $I_C=0.5\text{mA}$	1200	-	-	V
Collector-emitter saturation voltage	$V_{CEsat}$	$V_{GE}=15\text{V}$ , $I_C=25\text{A}$	1.4	1.7	2.1	
Gate-emitter threshold voltage	$V_{GE(th)}$	$I_C=1\text{mA}$ , $V_{GE}=V_{CE}$	5.0	5.8	6.5	
Zero gate voltage collector current	$I_{CES}$	$V_{CE}=1200\text{V}$ , $V_{GE}=0\text{V}$	-	-	3.48	$\mu\text{A}$
Gate-emitter leakage current	$I_{GES}$	$V_{CE}=0\text{V}$ , $V_{GE}=20\text{V}$	-	-	600	nA
Integrated gate resistor	$r_G$		8			$\Omega$

## Electrical Characteristics <sup>3</sup>

Parameter	Symbol	Conditions	Value			Unit
			min.	typ.	max.	
Collector-emitter saturation voltage	$V_{CEsat}$	$V_{GE}=15\text{V}$ , $I_C=25\text{A}$ , $T_{vj}=150^{\circ}\text{C}$	-	2.2	-	V
Input capacitance	$C_{ies}$	$V_{CE}=25\text{V}$ , $V_{GE}=0\text{V}$ , $f=1\text{MHz}$ $T_{vj}=25^{\circ}\text{C}$	-	1860	-	pF
Reverse transfer capacitance	$C_{res}$		-	82	-	

<sup>2</sup> Depending on thermal properties of assembly.

<sup>3</sup> Not subject to production test - verified by design/characterization.

<sup>4</sup> Allowed number of short circuits: <1000; time between short circuits: >1s.



# SIGC32T120R3LE

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## Further Electrical Characteristics

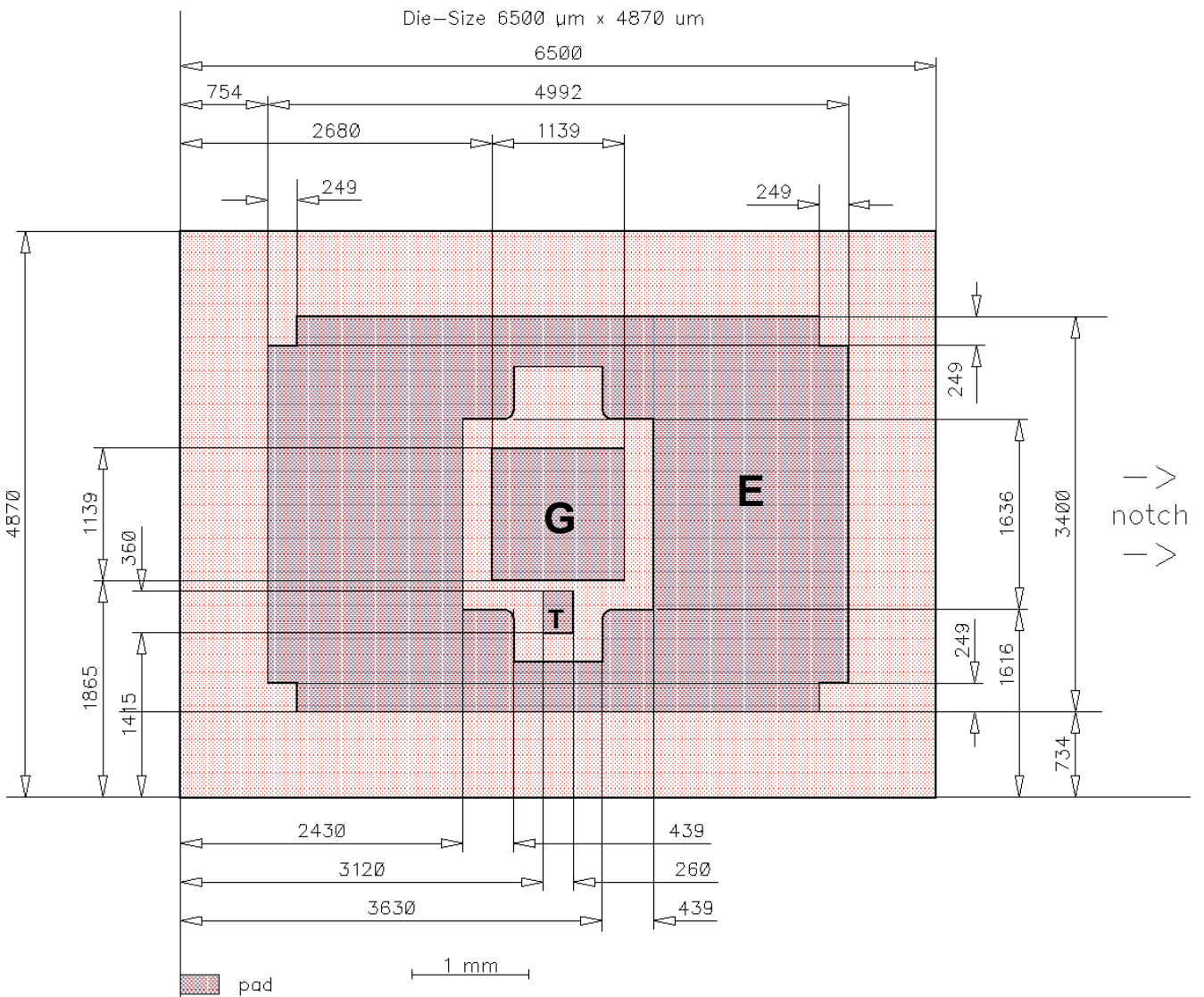
Switching characteristics and thermal properties are depending strongly on module design and mounting technology and can therefore not be specified for a bare die.

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Application example	IGW25T120	Rev. 2.4
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## Chip Drawing



**E** = Emitter  
**G** = Gate  
**T** = Test pad do not contact



# SIGC32T120R3LE

## Bare Die Product Specifics

Test coverage at wafer level cannot cover all application conditions. Therefore it is recommended to test all characteristics which are relevant for the application at package level, including RBSOA and SCSOA.

## Description

AQL 0.65 for visual inspection according to failure catalogue

Electrostatic Discharge Sensitive Device according to MIL-STD 883

## Revision History

Revision	Subjects (major changes since last revision)	Date
2.0	Release of final datasheet	31.01.2011
2.1	Additional basic types L7641N, L7641U, L7641F	27.06.2014
2.2	Minor changes, chip drawing	06.02.2015
2.3	Update disclaimer	19.08.2015

## Relevant Application Notes

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# SIGC32T120R3LE

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